

Notice of References Cited

Application/Control No.
09/430,350

Applicant(s)/Patent Under Reexam
Sutera et al.

Examiner
Hugh Jones

Art Unit
2123

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	Document Number Country Code-Number-Kind Code	Date MM-YYYY ¹	Name	Classification ²	
A	6,405,350 <input checked="" type="checkbox"/>	6/2002	Tawada	716	5
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NON-PATENT DOCUMENTS

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages					
U	Yang et al.; Deep submicron on-chip crosstalk; IEEE Proc. 16th Inst. Meas. Tech. Conf.; pp. 1788-1793; 5/1999.					
V	Davis et al.; Length, scaling, and material dependence of crosstalk between distributed RC Interconnects; IEEE Int. Conf. Interconnect Tech.; pp. 227-229; 5/1999.					
W	Oh et al.; A scaling scheme and optimization methodology for deep sub-micron interconnect; IEEE Int. Conf. Computer Design; pp. 320-325; 10/1996.					
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* A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

¹ Dates in MM-YYYY format are publication dates.

² Classifications may be U.S. or foreign.